

# STF7N95K3-VB Datasheet N-Channel 900 V (D-S) Super Junction Power MOSFET

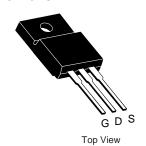
PRODUCT SUMMARY					
V <sub>DS</sub> (V)	90	00			
$R_{DS(on)}(\Omega)$	V <sub>GS</sub> = 10 V	0.95			
Q <sub>g</sub> (Max.) (nC)	200				
Q <sub>gs</sub> (nC)	24				
Q <sub>gd</sub> (nC)	110				
Configuration	Single				

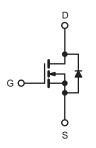
#### **FEATURES**

- Dynamic dV/dt Rating
- Repetitive Avalanche Rated
- Isolated Central Mounting Hole
- Fast Switching
- Ease of Paralleling
- Simple Drive Requirements
- Compliant to RoHS Directive 2002/95/EC



#### **TO-220 FULLPAK**





N-Channel MOSFET

<b>ABSOLUTE MAXIMUM RATINGS</b> (T <sub>C</sub> = 25 °C, unless otherwise noted)						
PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			$V_{DS}$	900	V	
Gate-Source Voltage			$V_{GS}$	± 20	v	
Continuous Drain Current	V <sub>GS</sub> at 10 V	T <sub>C</sub> = 25 °C	l <sub>D</sub>	7.0		
	VGS at 10 V	T <sub>C</sub> = 100 °C		5.5	Α	
Pulsed Drain Current <sup>a</sup>			I <sub>DM</sub>	21		
Linear Derating Factor				1.5	W/°C	
Single Pulse Avalanche Energy <sup>b</sup>			E <sub>AS</sub>	770	mJ	
Repetitive Avalanche Currenta			I <sub>AR</sub>	7.8	Α	
Repetitive Avalanche Energy <sup>a</sup>			E <sub>AR</sub>	19	mJ	
Maximum Power Dissipation $T_C = 25  ^{\circ}C$			$P_{D}$	65	W	
Peak Diode Recovery dV/dtc	•		dV/dt	2.0	V/ns	
Operating Junction and Storage Temperature Range			T <sub>J</sub> , T <sub>stg</sub>	- 55 to + 150	°C	
Soldering Recommendations (Peak Temperature)	for	10 s		300 <sup>d</sup>		
Mounting Torque	6-32 or M3 screw			10	lbf ⋅ in	
				1.1	N⋅m	

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b.  $V_{DD} = 50$  V, starting  $T_J = 25$  °C, L = 23 mH,  $R_g = 25$   $\Omega$ ,  $I_{AS} = 7.8$  A (see fig. 12). c.  $I_{SD} \le 7.8$  A, dl/dt  $\le 140$  A/ $\mu$ s,  $V_{DD} \le 600$  V,  $T_J \le 150$  °C. d. 1.6 mm from case.

<sup>\*</sup> Pb containing terminations are not RoHS compliant, exemptions may apply



THERMAL RESISTANCE RAT	INGS			
PARAMETER	SYMBOL	TYP.	MAX.	UNIT
Maximum Junction-to-Ambient	R <sub>thJA</sub>	-	40	
Case-to-Sink, Flat, Greased Surface	R <sub>thCS</sub>	0.24	-	°C/W
Maximum Junction-to-Case (Drain)	R <sub>thJC</sub>	-	0.65	

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static						•	
Drain-Source Breakdown Voltage	V <sub>DS</sub>	V <sub>GS</sub>	= 0 V, I <sub>D</sub> = 250 μA	900	-	-	V
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference	e to 25 °C, I <sub>D</sub> = 1 mA	-	0.98	-	V/°C
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> :	= V <sub>GS</sub> , I <sub>D</sub> = 250 μA	2.0	-	4.0	V
Gate-Source Leakage	I <sub>GSS</sub>		V <sub>GS</sub> = ± 20 V	-	-	± 100	nA
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> :	V <sub>DS</sub> = 900 V, V <sub>GS</sub> = 0 V		-	100	
		V <sub>DS</sub> = 720 \	V, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 125 °C	-	-	500	μA
Drain-Source On-State Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V	I <sub>D</sub> = 5.6 A <sup>b</sup>		0.95	-	Ω
Forward Transconductance	9fs	V <sub>DS</sub> =	= 100 V, I <sub>D</sub> = 5.6 A <sup>b</sup>	5.6	-	-	S
Dynamic							
Input Capacitance	C <sub>iss</sub>	V <sub>GS</sub> = 0 V,		-	3100	-	pF
Output Capacitance	C <sub>oss</sub>	1	$V_{DS} = 25 \text{ V},$		800	-	
Reverse Transfer Capacitance	$C_{rss}$	f = 1.0 MHz, see fig. 5		1	490	-	
Total Gate Charge	Qg		I <sub>D</sub> = 3.8 A, V <sub>DS</sub> = 400 V, see fig. 6 and 13 <sup>b</sup>	-	-	200	nC
Gate-Source Charge	$Q_{gs}$	V <sub>GS</sub> = 10 V		1	-	24	
Gate-Drain Charge	$Q_{gd}$			ı	-	110	
Turn-On Delay Time	t <sub>d(on)</sub>	$V_{DD} = 400 \text{ V}, I_{D} = 5.6 \text{ A},$ $R_{g} = 6.2 \Omega, R_{D} = 52 \Omega$ see fig. $10^{b}$		ı	19	-	- ns
Rise Time	t <sub>r</sub>			1	38	-	
Turn-Off Delay Time	$t_{d(off)}$			1	120	-	
Fall Time	t <sub>f</sub>			ı	39	-	
Internal Drain Inductance	$L_D$	Between lead, 6 mm (0.25") from package and center of die contact		-	5.0	-	ъЦ
Internal Source Inductance	L <sub>S</sub>			-	13	-	- nH
Drain-Source Body Diode Characteristic	s					•	
Continuous Source-Drain Diode Current	I <sub>S</sub>	MOSFET symbol showing the integral reverse p - n junction diode		-	-	5.0	_
Pulsed Diode Forward Current <sup>a</sup>	I <sub>SM</sub>			-	-	21	A
Body Diode Voltage	V <sub>SD</sub>	T <sub>J</sub> = 25 °C	T <sub>J</sub> = 25 °C, I <sub>S</sub> = 5.6 A, V <sub>GS</sub> = 0 V <sup>b</sup>		-	1.8	V
Body Diode Reverse Recovery Time	t <sub>rr</sub>	T <sub>J</sub> = 25 °C, I <sub>F</sub> = 5.6 A, dl/dt = 100 A/μs <sup>b</sup>		-	650	980	ns
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>			-	3.8	5.7	μC
Forward Turn-On Time	t <sub>on</sub>	Intrinsic turn-on time is negligible (turn-on is dominated by L <sub>S</sub> and L				L <sub>D</sub> )	

#### Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. Pulse width  $\leq$  300 µs; duty cycle  $\leq$  2 %.



#### TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

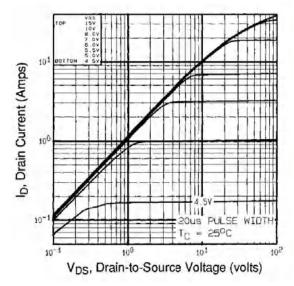


Fig. 1 - Typical Output Characteristics, T<sub>C</sub> = 25 °C

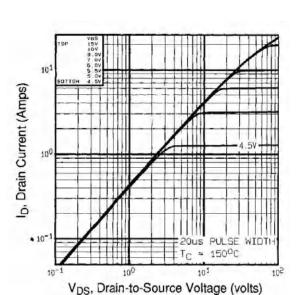


Fig. 2 - Typical Output Characteristics,  $T_C$  = 150 °C

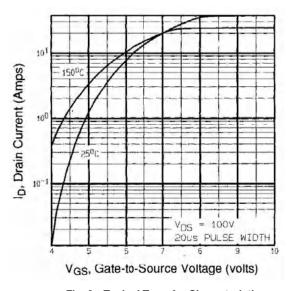


Fig. 3 - Typical Transfer Characteristics

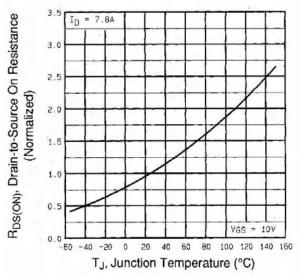


Fig. 4 - Normalized On-Resistance vs. Temperature



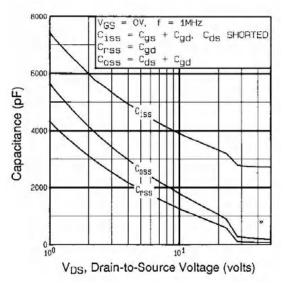


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

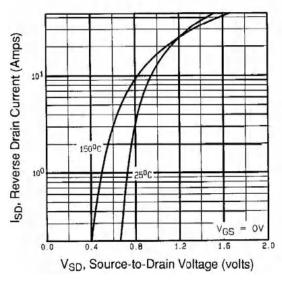


Fig. 7 - Typical Source-Drain Diode Forward Voltage

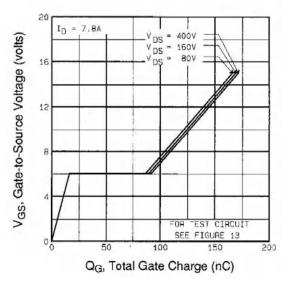


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

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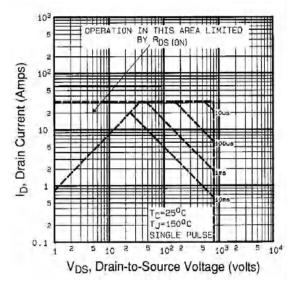


Fig. 8 - Maximum Safe Operating Area



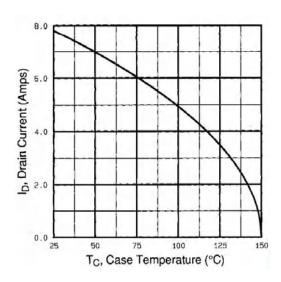


Fig. 9 - Maximum Drain Current vs. Case Temperature

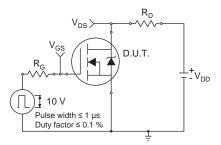


Fig. 10a - Switching Time Test Circuit

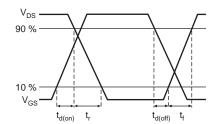


Fig. 10b - Switching Time Waveforms

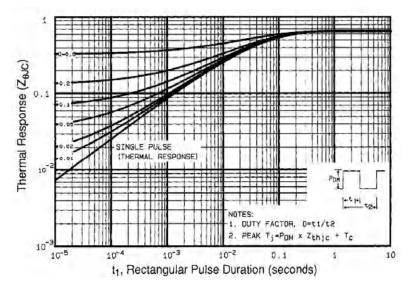


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case



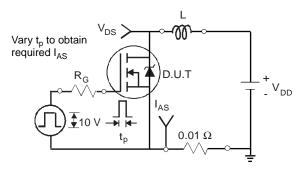


Fig. 12a - Unclamped Inductive Test Circuit

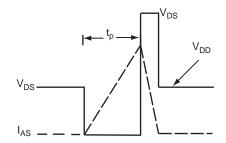


Fig. 12b - Unclamped Inductive Waveforms

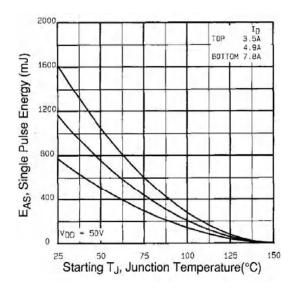


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

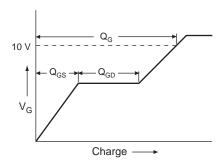


Fig. 13a - Basic Gate Charge Waveform

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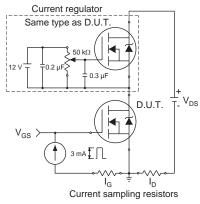
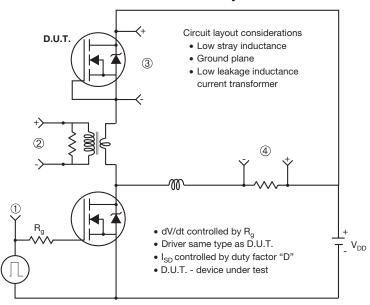


Fig. 13b - Gate Charge Test Circuit



#### Peak Diode Recovery dV/dt Test Circuit



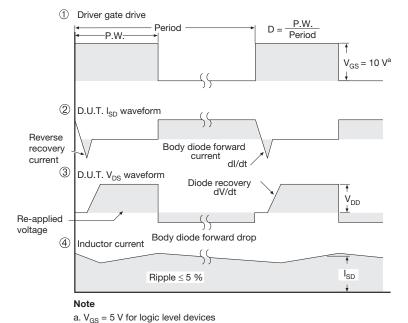
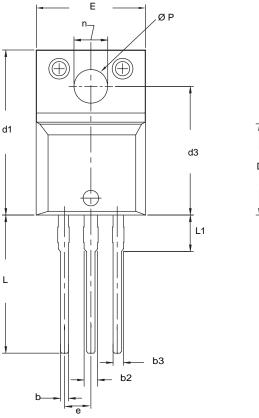
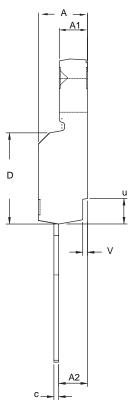


Fig. 14 - For N-Channel



### **TO-220 FULLPAK (HIGH VOLTAGE)**





DIM.	MILLIN	MILLIMETERS		HES
	MIN.	MAX.	MIN.	MAX.
Α	4.570	4.830	0.180	0.190
A1	2.570	2.830	0.101	0.111
A2	2.510	2.850	0.099	0.112
b	0.622	0.890	0.024	0.035
b2	1.229	1.400	0.048	0.055
b3	1.229	1.400	0.048	0.055
С	0.440	0.629	0.017	0.025
D	8.650	9.800	0.341	0.386
d1	15.88	16.120	0.622	0.635
d3	12.300	12.920	0.484	0.509
E	10.360	10.630	0.408	0.419
е	2.54	BSC	0.100	BSC
L	13.200	13.730	0.520	0.541
L1	3.100	3.500	0.122	0.138
n	6.050	6.150	0.238	0.242
ØΡ	3.050	3.450	0.120	0.136
u	2.400	2.500	0.094	0.098
V	0.400	0.500	0.016	0.020

ECN: X09-0126-Rev. B, 26-Oct-09 DWG: 5972

#### **Notes**

- To be used only for process drawing.
   These dimensions apply to all TO-220, FULLPAK leadframe versions 3 leads.
   All critical dimensions should C meet C<sub>pk</sub> > 1.33.
   All dimensions include burrs and plating thickness.

- 5. No chipping or package damage.



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